E.J. Lattice Semiconductor Corporation - <u>LFE3-35EA-7FN484I Datasheet</u>



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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	4125
Number of Logic Elements/Cells	33000
Total RAM Bits	1358848
Number of I/O	295
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-35ea-7fn484i

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ROM Mode

ROM mode uses the LUT logic; hence, Slices 0 through 3 can be used in ROM mode. Preloading is accomplished through the programming interface during PFU configuration.

For more information, please refer to TN1179, LatticeECP3 Memory Usage Guide.

Routing

There are many resources provided in the LatticeECP3 devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The LatticeECP3 family has an enhanced routing architecture that produces a compact design. The Diamond and ispLEVER design software tool suites take the output of the synthesis tool and places and routes the design.

sysCLOCK PLLs and DLLs

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The devices in the LatticeECP3 family support two to ten full-featured General Purpose PLLs.

General Purpose PLL

The architecture of the PLL is shown in Figure 2-4. A description of the PLL functionality follows.

CLKI is the reference frequency (generated either from the pin or from routing) for the PLL. CLKI feeds into the Input Clock Divider block. The CLKFB is the feedback signal (generated from CLKOP, CLKOS or from a user clock pin/logic). This signal feeds into the Feedback Divider. The Feedback Divider is used to multiply the reference frequency.

Both the input path and feedback signals enter the Phase Frequency Detect Block (PFD) which detects first for the frequency, and then the phase, of the CLKI and CLKFB are the same which then drives the Voltage Controlled Oscillator (VCO) block. In this block the difference between the input path and feedback signals is used to control the frequency and phase of the oscillator. A LOCK signal is generated by the VCO to indicate that the VCO has locked onto the input clock signal. In dynamic mode, the PLL may lose lock after a dynamic delay adjustment and not relock until the t_{LOCK} parameter has been satisfied.

The output of the VCO then enters the CLKOP divider. The CLKOP divider allows the VCO to operate at higher frequencies than the clock output (CLKOP), thereby increasing the frequency range. The Phase/Duty Cycle/Duty Trim block adjusts the phase and duty cycle of the CLKOS signal. The phase/duty cycle setting can be pre-programmed or dynamically adjusted. A secondary divider takes the CLKOP or CLKOS signal and uses it to derive lower frequency outputs (CLKOK).

The primary output from the CLKOP divider (CLKOP) along with the outputs from the secondary dividers (CLKOK and CLKOK2) and Phase/Duty select (CLKOS) are fed to the clock distribution network.

The PLL allows two methods for adjusting the phase of signal. The first is referred to as Fine Delay Adjustment. This inserts up to 16 nominal 125 ps delays to be applied to the secondary PLL output. The number of steps may be set statically or from the FPGA logic. The second method is referred to as Coarse Phase Adjustment. This allows the phase of the rising and falling edge of the secondary PLL output to be adjusted in 22.5 degree steps. The number of steps may be set statically or from the FPGA logic.



PLL/DLL Cascading

LatticeECP3 devices have been designed to allow certain combinations of PLL and DLL cascading. The allowable combinations are:

- PLL to PLL supported
- PLL to DLL supported

The DLLs in the LatticeECP3 are used to shift the clock in relation to the data for source synchronous inputs. PLLs are used for frequency synthesis and clock generation for source synchronous interfaces. Cascading PLL and DLL blocks allows applications to utilize the unique benefits of both DLLs and PLLs.

For further information about the DLL, please see the list of technical documentation at the end of this data sheet.

PLL/DLL PIO Input Pin Connections

All LatticeECP3 devices contains two DLLs and up to ten PLLs, arranged in quadrants. If a PLL and a DLL are next to each other, they share input pins as shown in the Figure 2-7.

Figure 2-7. Sharing of PIO Pins by PLLs and DLLs in LatticeECP3 Devices



Note: Not every PLL has an associated DLL.

Clock Dividers

LatticeECP3 devices have two clock dividers, one on the left side and one on the right side of the device. These are intended to generate a slower-speed system clock from a high-speed edge clock. The block operates in a ÷2, ÷4 or ÷8 mode and maintains a known phase relationship between the divided down clock and the high-speed clock based on the release of its reset signal. The clock dividers can be fed from selected PLL/DLL outputs, the Slave Delay lines, routing or from an external clock input. The clock divider outputs serve as primary clock sources and feed into the clock distribution network. The Reset (RST) control signal resets input and asynchronously forces all outputs to low. The RELEASE signal releases outputs synchronously to the input clock. For further information on clock dividers, please see TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide. Figure 2-8 shows the clock divider connections.



Figure 2-10. Primary Clock Sources for LatticeECP3-35



Note: Clock inputs can be configured in differential or single-ended mode.

Figure 2-11. Primary Clock Sources for LatticeECP3-70, -95, -150



Note: Clock inputs can be configured in differential or single-ended mode.



Figure 2-20. Sources of Edge Clock (Left and Right Edges)



Figure 2-21. Sources of Edge Clock (Top Edge)



The edge clocks have low injection delay and low skew. They are used to clock the I/O registers and thus are ideal for creating I/O interfaces with a single clock signal and a wide data bus. They are also used for DDR Memory or Generic DDR interfaces.



MULTADDSUB DSP Element

In this case, the operands AA and AB are multiplied and the result is added/subtracted with the result of the multiplier operation of operands BA and BB. The user can enable the input, output and pipeline registers. Figure 2-29 shows the MULTADDSUB sysDSP element.

Figure 2-29. MULTADDSUB





MULTADDSUBSUM DSP Element

In this case, the operands AA and AB are multiplied and the result is added/subtracted with the result of the multiplier operation of operands BA and BB of Slice 0. Additionally, the operands AA and AB are multiplied and the result is added/subtracted with the result of the multiplier operation of operands BA and BB of Slice 1. The results of both addition/subtractions are added by the second ALU following the slice cascade path. The user can enable the input, output and pipeline registers. Figure 2-30 and Figure 2-31 show the MULTADDSUBSUM sysDSP element.

Figure 2-30. MULTADDSUBSUM Slice 0





Please see TN1177, LatticeECP3 sysIO Usage Guide for on-chip termination usage and value ranges.

Equalization Filter

Equalization filtering is available for single-ended inputs on both true and complementary I/Os, and for differential inputs on the true I/Os on the left, right, and top sides. Equalization is required to compensate for the difficulty of sampling alternating logic transitions with a relatively slow slew rate. It is considered the most useful for the Input DDRX2 modes, used in DDR3 memory, LVDS, or TRLVDS signaling. Equalization filter acts as a tunable filter with settings to determine the level of correction. In the LatticeECP3 devices, there are four settings available: 0 (none), 1, 2 and 3. The default setting is 0. The equalization logic resides in the sysI/O buffers, the two bits of setting is set uniquely in each input IOLOGIC block. Therefore, each sysI/O can have a unique equalization setting within a DQS-12 group.

Hot Socketing

LatticeECP3 devices have been carefully designed to ensure predictable behavior during power-up and powerdown. During power-up and power-down sequences, the I/Os remain in tri-state until the power supply voltage is high enough to ensure reliable operation. In addition, leakage into I/O pins is controlled within specified limits. Please refer to the Hot Socketing Specifications in the DC and Switching Characteristics in this data sheet.

SERDES and PCS (Physical Coding Sublayer)

LatticeECP3 devices feature up to 16 channels of embedded SERDES/PCS arranged in quads at the bottom of the devices supporting up to 3.2Gbps data rate. Figure 2-40 shows the position of the quad blocks for the LatticeECP3-150 devices. Table 2-14 shows the location of available SERDES Quads for all devices.

The LatticeECP3 SERDES/PCS supports a range of popular serial protocols, including:

- PCI Express 1.1
- Ethernet (XAUI, GbE 1000 Base CS/SX/LX and SGMII)
- Serial RapidIO
- SMPTE SDI (3G, HD, SD)
- CPRI
- SONET/SDH (STS-3, STS-12, STS-48)

Each quad contains four dedicated SERDES for high speed, full duplex serial data transfer. Each quad also has a PCS block that interfaces to the SERDES channels and contains protocol specific digital logic to support the standards listed above. The PCS block also contains interface logic to the FPGA fabric. All PCS logic for dedicated protocol support can also be bypassed to allow raw 8-bit or 10-bit interfaces to the FPGA fabric.

Even though the SERDES/PCS blocks are arranged in quads, multiple baud rates can be supported within a quad with the use of dedicated, per channel \div 1, \div 2 and \div 11 rate dividers. Additionally, multiple quads can be arranged together to form larger data pipes.

For information on how to use the SERDES/PCS blocks to support specific protocols, as well on how to combine multiple protocols and baud rates within a device, please refer to TN1176, LatticeECP3 SERDES/PCS Usage Guide.



MCCLK (MHz)	MCCLK (MHz)
	10
2.5 ¹	13
4.3	15 ²
5.4	20
6.9	26
8.1	33 ³
9.2	

 Table 2-16. Selectable Master Clock (MCCLK) Frequencies During Configuration (Nominal)

1. Software default MCCLK frequency. Hardware default is 3.1 MHz.

2. Maximum MCCLK with encryption enabled.

3. Maximum MCCLK without encryption.

Density Shifting

The LatticeECP3 family is designed to ensure that different density devices in the same family and in the same package have the same pinout. Furthermore, the architecture ensures a high success rate when performing design migration from lower density devices to higher density devices. In many cases, it is also possible to shift a lower utilization design targeted for a high-density device to a lower density device. However, the exact details of the final resource utilization will impact the likelihood of success in each case. An example is that some user I/Os may become No Connects in smaller devices in the same package. Refer to the LatticeECP3 Pin Migration Tables and Diamond software for specific restrictions and limitations.



sysl/O Recommended Operating Conditions

	V _{CCIO}			V _{REF} (V)			
Standard	Min.	Тур.	Max.	Min.	Тур.	Max.	
LVCMOS33 ²	3.135	3.3	3.465	—	—	—	
LVCMOS33D	3.135	3.3	3.465	—	—	—	
LVCMOS25 ²	2.375	2.5	2.625	—	—	—	
LVCMOS18	1.71	1.8	1.89	—	—	—	
LVCMOS15	1.425	1.5	1.575	—	—	—	
LVCMOS12 ²	1.14	1.2	1.26	—	—	—	
LVTTL33 ²	3.135	3.3	3.465	—	—	—	
PCI33	3.135	3.3	3.465	—	—	—	
SSTL15 ³	1.43	1.5	1.57	0.68	0.75	0.9	
SSTL18_I, II ²	1.71	1.8	1.89	0.833	0.9	0.969	
SSTL25_I, II ²	2.375	2.5	2.625	1.15	1.25	1.35	
SSTL33_I, II ²	3.135	3.3	3.465	1.3	1.5	1.7	
HSTL15_l ²	1.425	1.5	1.575	0.68	0.75	0.9	
HSTL18_I, II ²	1.71	1.8	1.89	0.816	0.9	1.08	
LVDS25 ²	2.375	2.5	2.625	—	—	—	
LVDS25E	2.375	2.5	2.625	—	—	—	
MLVDS ¹	2.375	2.5	2.625	—	—	—	
LVPECL33 ^{1, 2}	3.135	3.3	3.465	—	—	—	
Mini LVDS	2.375	2.5	2.625	—	—	—	
BLVDS25 ^{1, 2}	2.375	2.5	2.625		—	—	
RSDS ²	2.375	2.5	2.625	—	—	—	
RSDSE ^{1, 2}	2.375	2.5	2.625	—	—	—	
TRLVDS	3.14	3.3	3.47	—	—	—	
PPLVDS	3.14/2.25	3.3/2.5	3.47/2.75	—	—	—	
SSTL15D ³	1.43	1.5	1.57		—	—	
SSTL18D_I ^{2, 3} , II ^{2, 3}	1.71	1.8	1.89		—	—	
SSTL25D_ I ² , II ²	2.375	2.5	2.625	—	—	—	
SSTL33D_ I ² , II ²	3.135	3.3	3.465	—	—	—	
HSTL15D_ I ²	1.425	1.5	1.575	_	—	—	
HSTL18D_ I ² , II ²	1.71	1.8	1.89	—	—	—	

1. Inputs on chip. Outputs are implemented with the addition of external resistors.

2. For input voltage compatibility, see TN1177, LatticeECP3 sysIO Usage Guide.

3. VREF is required when using Differential SSTL to interface to DDR memory.



LVDS25E

The top and bottom sides of LatticeECP3 devices support LVDS outputs via emulated complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The scheme shown in Figure 3-1 is one possible solution for point-to-point signals.





Table 3-1. LVDS25E DC Conditions

Parameter	Description	Typical	Units
V _{CCIO}	Output Driver Supply (+/-5%)	2.50	V
Z _{OUT}	Driver Impedance	20	Ω
R _S	Driver Series Resistor (+/-1%)	158	Ω
R _P	Driver Parallel Resistor (+/-1%)	140	Ω
R _T	Receiver Termination (+/-1%)	100	Ω
V _{OH}	Output High Voltage	1.43	V
V _{OL}	Output Low Voltage	1.07	V
V _{OD}	Output Differential Voltage	0.35	V
V _{CM}	Output Common Mode Voltage	1.25	V
Z _{BACK}	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	6.03	mA

LVCMOS33D

All I/O banks support emulated differential I/O using the LVCMOS33D I/O type. This option, along with the external resistor network, provides the system designer the flexibility to place differential outputs on an I/O bank with 3.3 V V_{CCIO}. The default drive current for LVCMOS33D output is 12 mA with the option to change the device strength to 4 mA, 8 mA, 16 mA or 20 mA. Follow the LVCMOS33 specifications for the DC characteristics of the LVCMOS33D.



LVPECL33

The LatticeECP3 devices support the differential LVPECL standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-3 is one possible solution for point-to-point signals.

Figure 3-3. Differential LVPECL33



Table 3-3. LVPECL33 DC Conditions¹

Parameter	Description	Typical	Units
V _{CCIO}	Output Driver Supply (+/-5%)	3.30	V
Z _{OUT}	Driver Impedance	10	Ω
R _S	Driver Series Resistor (+/-1%)	93	Ω
R _P	Driver Parallel Resistor (+/-1%)	196	Ω
R _T	Receiver Termination (+/-1%)	100	Ω
V _{OH}	Output High Voltage	2.05	V
V _{OL}	Output Low Voltage	1.25	V
V _{OD}	Output Differential Voltage	0.80	V
V _{CM}	Output Common Mode Voltage	1.65	V
Z _{BACK}	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	12.11	mA

Over Recommended Operating Conditions

1. For input buffer, see LVDS table.



LatticeECP3 External Switching Characteristics (Continued)^{1, 2, 3, 13}

Over Recommended Commercial	Operating Conditions
------------------------------------	-----------------------------

			-8		-7		-6		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
Generic DDRX2 Ou	tput with Clock and Data (>10 Bits	Wide) Centered at Pir	n Using I	PLL (GDI	DRX2_TX	.PLL.Cer	ntered) ¹⁰		
Left and Right Side	es								
t _{DVBGDDR}	Data Valid Before CLK	All ECP3EA Devices	285	_	370	_	431	—	ps
t _{DVAGDDR}	Data Valid After CLK	All ECP3EA Devices	285	_	370	_	432	_	ps
f _{MAX_GDDR}	DDRX2 Clock Frequency	All ECP3EA Devices	_	500	—	420	—	375	MHz
Memory Interface		•							
DDR/DDR2 I/O Pin	Parameters (Input Data are Strobe	Edge Aligned, Output	ut Strobe	e Edge is	Data Ce	ntered)4			
t _{DVADQ}	Data Valid After DQS (DDR Read)	All ECP3 Devices	—	0.225		0.225		0.225	UI
t _{DVEDQ}	Data Hold After DQS (DDR Read)	All ECP3 Devices	0.64	—	0.64	—	0.64	—	UI
t _{DQVBS}	Data Valid Before DQS	All ECP3 Devices	0.25	—	0.25	_	0.25	_	UI
t _{DQVAS}	Data Valid After DQS	All ECP3 Devices	0.25	—	0.25	_	0.25	_	UI
f _{MAX_DDR}	DDR Clock Frequency	All ECP3 Devices	95	200	95	200	95	166	MHz
f _{MAX_DDR2}	DDR2 clock frequency	All ECP3 Devices	125	266	125	200	125	166	MHz
DDR3 (Using PLL f	or SCLK) I/O Pin Parameters								
t _{DVADQ}	Data Valid After DQS (DDR Read)	All ECP3 Devices	_	0.225		0.225		0.225	UI
t _{DVEDQ}	Data Hold After DQS (DDR Read)	All ECP3 Devices	0.64	_	0.64	_	0.64	—	UI
t _{DQVBS}	Data Valid Before DQS	All ECP3 Devices	0.25	_	0.25	_	0.25	—	UI
t _{DQVAS}	Data Valid After DQS	All ECP3 Devices	0.25	_	0.25	_	0.25	—	UI
f _{MAX_DDR3}	DDR3 clock frequency	All ECP3 Devices	300	400	266	333	266	300	MHz
DDR3 Clock Timing	9								
t _{CH} (avg) ⁹	Average High Pulse Width	All ECP3 Devices	0.47	0.53	0.47	0.53	0.47	0.53	UI
t _{CL} (avg) ⁹	Average Low Pulse Width	All ECP3 Devices	0.47	0.53	0.47	0.53	0.47	0.53	UI
t _{JIT} (per, lck) ⁹	Output Clock Period Jitter During DLL Locking Period	All ECP3 Devices	-90	90	-90	90	-90	90	ps
t _{JIT} (cc, lck) ⁹	Output Cycle-to-Cycle Period Jit- ter During DLL Locking Period	All ECP3 Devices	_	180	—	180	—	180	ps

1. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from the Diamond or ispLEVER software.

2. General I/O timing numbers based on LVCMOS 2.5, 12mA, Fast Slew Rate, 0pf load.

3. Generic DDR timing numbers based on LVDS I/O.

4. DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18.

5. DDR3 timing numbers based on SSTL15.

6. Uses LVDS I/O standard.

7. The current version of software does not support per bank skew numbers; this will be supported in a future release.

8. Maximum clock frequencies are tested under best case conditions. System performance may vary upon the user environment.

9. Using settings generated by IPexpress.

10. These numbers are generated using best case PLL located in the center of the device.

11. Uses SSTL25 Class II Differential I/O Standard.

12. All numbers are generated with ispLEVER 8.1 software.

13. For details on -9 speed grade devices, please contact your Lattice Sales Representative.



Table 3-11. Periodic Receiver Jitter Tolerance Specification

Description	Frequency	Condition	Min.	Тур.	Max.	Units
Periodic	2.97 Gbps	600 mV differential eye	_	_	0.24	UI, p-p
Periodic	2.5 Gbps	600 mV differential eye	_	—	0.22	UI, p-p
Periodic	1.485 Gbps	600 mV differential eye	—	—	0.24	UI, p-p
Periodic	622 Mbps	600 mV differential eye	_	_	0.15	UI, p-p
Periodic	150 Mbps	600 mV differential eye	_		0.5	UI, p-p

Note: Values are measured with PRBS 2⁷–1, all channels operating, FPGA Logic active, I/Os around SERDES pins quiet, voltages are nominal, room temperature.



SERDES External Reference Clock

The external reference clock selection and its interface are a critical part of system applications for this product. Table 3-12 specifies reference clock requirements, over the full range of operating conditions.

Symbol	Description	Min.	Тур.	Max.	Units
F _{REF}	Frequency range	15	_	320	MHz
F _{REF-PPM}	Frequency tolerance ¹	-1000	_	1000	ppm
V _{REF-IN-SE}	Input swing, single-ended clock ²	200	_	V _{CCA}	mV, p-p
V _{REF-IN-DIFF}	Input swing, differential clock	200	_	2*V _{CCA}	mV, p-p differential
V _{REF-IN}	Input levels	0	_	V _{CCA} + 0.3	V
D _{REF}	Duty cycle ³	40	_	60	%
T _{REF-R}	Rise time (20% to 80%)	200	500	1000	ps
T _{REF-F}	Fall time (80% to 20%)	200	500	1000	ps
Z _{REF-IN-TERM-DIFF}	Differential input termination	-20%	100/2K	+20%	Ohms
C _{REF-IN-CAP}	Input capacitance	_	—	7	pF

Table 3-12. External Reference Clock Specification (refclkp/refclkn)

1. Depending on the application, the PLL_LOL_SET and CDR_LOL_SET control registers may be adjusted for other tolerance values as described in TN1176, LatticeECP3 SERDES/PCS Usage Guide.

2. The signal swing for a single-ended input clock must be as large as the p-p differential swing of a differential input clock to get the same gain at the input receiver. Lower swings for the clock may be possible, but will tend to increase jitter.

3. Measured at 50% amplitude.

Figure 3-13. SERDES External Reference Clock Waveforms





Figure 3-14. Jitter Transfer – 3.125 Gbps



Figure 3-15. Jitter Transfer – 2.5 Gbps





Figure 3-19. Test Loads

Test Loads



















Signal Descriptions (Cont.)

Signal Name	I/O	Description
[LOC]DQS[num]	I/O	DQ input/output pads: T (top), R (right), B (bottom), L (left), DQS, num = ball function number.
[LOC]DQ[num]	I/O	DQ input/output pads: T (top), R (right), B (bottom), L (left), DQ, associated DQS number.
Test and Programming (Dedicated Pi	ns)	
TMS	I	Test Mode Select input, used to control the 1149.1 state machine. Pull-up is enabled during configuration.
тск	I	Test Clock input pin, used to clock the 1149.1 state machine. No pull-up enabled.
TDI	I	Test Data in pin. Used to load data into device using 1149.1 state machine. After power-up, this TAP port can be activated for configuration by sending appropriate command. (Note: once a configuration port is selected it is locked. Another configuration port cannot be selected until the power-up sequence). Pull-up is enabled during configuration.
TDO	0	Output pin. Test Data Out pin used to shift data out of a device using 1149.1.
VCCJ	—	Power supply pin for JTAG Test Access Port.
Configuration Pads (Used During sys	CONFIG	G)
CFG[2:0]	I	Mode pins used to specify configuration mode values latched on rising edge of INITN. During configuration, a pull-up is enabled. These are dedicated pins.
INITN	I/O	Open Drain pin. Indicates the FPGA is ready to be configured. During configuration, a pull-up is enabled. It is a dedicated pin.
PROGRAMN	Ι	Initiates configuration sequence when asserted low. This pin always has an active pull-up. It is a dedicated pin.
DONE	I/O	Open Drain pin. Indicates that the configuration sequence is complete, and the startup sequence is in progress. It is a dedicated pin.
ССГК	Ι	Input Configuration Clock for configuring an FPGA in Slave SPI, Serial, and CPU modes. It is a dedicated pin.
MCLK	I/O	Output Configuration Clock for configuring an FPGA in SPI, SPIm, and Master configuration modes.
BUSY/SISPI	0	Parallel configuration mode busy indicator. SPI/SPIm mode data output.
CSN/SN/OEN	I/O	Parallel configuration mode active-low chip select. Slave SPI chip select. Parallel burst Flash output enable.
CS1N/HOLDN/RDY	I	Parallel configuration mode active-low chip select. Slave SPI hold input.
WRITEN	Ι	Write enable for parallel configuration modes.
DOUT/CSON/CSSPI1N	0	Serial data output. Chip select output. SPI/SPIm mode chip select.
		sysCONFIG Port Data I/O for Parallel mode. Open drain during configuration.
D[0]/SPIFASTN	I/O	sysCONFIG Port Data I/O for SPI or SPIm. When using the SPI or SPIm mode, this pin should either be tied high or low, must not be left floating. Open drain during configuration.
D1	I/O	Parallel configuration I/O. Open drain during configuration.
D2	I/O	Parallel configuration I/O. Open drain during configuration.
D3/SI	I/O	Parallel configuration I/O. Slave SPI data input. Open drain during configura- tion.
D4/SO	I/O	Parallel configuration I/O. Slave SPI data output. Open drain during configura- tion.
D5	I/O	Parallel configuration I/O. Open drain during configuration.
D6/SPID1	I/O	Parallel configuration I/O. SPI/SPIm data input. Open drain during configura- tion.



LatticeECP3 Family Data Sheet Supplemental Information

February 2014

Data Sheet DS1021

For Further Information

A variety of technical notes for the LatticeECP3 family are available on the Lattice website at <u>www.latticesemi.com</u>.

- TN1169, LatticeECP3 sysCONFIG Usage Guide
- TN1176, LatticeECP3 SERDES/PCS Usage Guide
- TN1177, LatticeECP3 sysIO Usage Guide
- TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide
- TN1179, LatticeECP3 Memory Usage Guide
- TN1180, LatticeECP3 High-Speed I/O Interface
- TN1181, Power Consumption and Management for LatticeECP3 Devices
- TN1182, LatticeECP3 sysDSP Usage Guide
- TN1184, LatticeECP3 Soft Error Detection (SED) Usage Guide
- TN1189, LatticeECP3 Hardware Checklist
- TN1215, LatticeECP2MS and LatticeECP2S Devices
- TN1216, LatticeECP2/M and LatticeECP3 Dual Boot Feature Advanced Security Encryption Key Programming Guide for LatticeECP3
- TN1222, LatticeECP3 Slave SPI Port User's Guide

For further information on interface standards refer to the following websites:

- JEDEC Standards (LVTTL, LVCMOS, SSTL, HSTL): www.jedec.org
- PCI: www.pcisig.com

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LatticeECP3 Family Data Sheet Revision History

March 2015

Data Sheet DS1021

Date	Version	Section	Change Summary
March 2015	2.8EA	Pinout Information All	Updated Package Pinout Information section. Changed reference to http://www.latticesemi.com/Products/FPGAandCPLD/LatticeECP3.
			Minor style/formatting changes.
April 2014	02.7EA	DC and Switching	Updated LatticeECP3 Supply Current (Standby) table power numbers.
		Characteristics	Removed speed grade -9 timing numbers in the following sections: — Typical Building Block Function Performance — LatticeECP3 External Switching Characteristics — LatticeECP3 Internal Switching Characteristics — LatticeECP3 Family Timing Adders
		Ordering Information	Removed ordering information for -9 speed grade devices.
March 2014	02.6EA	DC and Switching Characteristics	Added information to the sysl/O Single-Ended DC Electrical Character- istics section footnote.
February 2014	02.5EA	DC and Switching Characteristics	Updated Hot Socketing Specifications table. Changed ${\rm I}_{Pw}$ to ${\rm I}_{PD}$ in footnote 3.
			Updated the following figures: — Figure 3-25, sysCONFIG Port Timing — Figure 3-27, Wake-Up Timing
		Supplemental Information	Added technical note references.
September 2013	02.4EA	2.4EA DC and Switching Characteristics	Updated the Wake-Up Timing Diagram
			Added the following figures: — Master SPI POR Waveforms — SPI Configuration Waveforms — Slave SPI HOLDN Waveforms
			Added tIODISS and tIOENSS parameters in LatticeECP3 sysCONFIG Port Timing Specifications table.
June 2013	02.3EA	Architecture	sysl/O Buffer Banks text section – Updated description of "Top (Bank 0 and Bank 1) and Bottom syslO Buffer Pairs (Single-Ended Outputs Only)" for hot socketing information.
			sysl/O Buffer Banks text section – Updated description of "Configuration Bank sysl/O Buffer Pairs (Single-Ended Outputs, Only on Shared Pins When Not Used by Configuration)" for PCI clamp information.
			On-Chip Oscillator section – clarified the speed of the internal CMOS oscillator (130 MHz +/- 15%).
			Architecture Overview section – Added information on the state of the register on power up and after configuration.
		DC and Switching Characteristics	sysl/O Recommended Operating Conditions table – Removed reference to footnote 1 from RSDS standard.
			sysl/O Single-Ended DC Electrical Characteristics table – Modified foot- note 1.
			Added Oscillator Output Frequency table.
			LatticeECP3 sysCONFIG Port Timing Specifications table – Updated min. column for t _{CODO} parameter.
			LatticeECP3 Family Timing Adders table – Description column, references to VCCIO = 3.0V changed to 3.3V. For PPLVDS, description changed from emulated to True LVDS and VCCIO = 2.5V changed to VCCIO = 2.5V or 3.3V.

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